

<b>Notice of References Cited</b>	Application/Control No. 10/565,636		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Haissa Philogene		Art Unit 2821	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,136,032	11-2006	Onozawa et al.	345/60
*	B	US-6,756,742	06-2004	Tsai et al.	315/169.3
*	C	US-6,738,033	05-2004	Hibino et al.	345/60
*	D	US-6,034,482	03-2000	Kanazawa et al.	315/169.4
*	E	US-7,471,265	12-2008	Kim et al.	345/60
*	F	US-6,061,040	05-2000	Onodera et al.	345/67
*	G	US-2004/0183764	09-2004	Kim et al.	345/088
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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